

Search Notes

Application/Control No.

10/538,825

Examiner

Derek S. Chapel

Applicant(s)/Patent under
Reexamination

YE, CHUN

Art Unit

2872

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Arnel Lavarias about the case.	10/16/2006	DSC
EAST Update Search, see attached.	10/16/2006	DSC